



RF EXPOSURE REPORT

Applicant:	Particle Industries, Inc				
Address:	126 Post St,4th floor, San Francisco, CA 94108 USA				
Manufacturer or Supplier:	Particle Industries, Inc				
Address:	126 Post St,4th floor, San Francisco, CA 94108 USA				
Product:	Electron				
Brand Name:	Particle				
Model Name:	ELC402, ELC404				
IC ID:	8585A-2AGQN4NNN				
Date of tests:	Oct. 17, 2019 ~ Dec. 05, 2019				
The submitted sample of the above equipment has been tested for according to the requirements of the following standards:					
 RSS-102 Issue 5 (March, 2015) ☑ IEEE C95.3 					
CONCLUSION: The submitted sample was found to <u>COMPLY</u> with the test requirement					
Remark: This test	report is for internal customer use of	only, not as a final certification test report.			
Prepared by Alex ChenApproved by Luke LuEngineer / Mobile DepartmentManager / Mobile Department					
Alex lupe lu					
Date: Dec. 23, 2020 Date: Dec. 23, 2020 This report is governed by, and incorporates by reference, CPS Conditions of Service as posted at the date of issuance of this report at					
In seport is governed by, and incorporates by reference, CPS Containons of Service as posted at the date or issuance of this report at the date or issuance of the issuance of this report at the date or issuance of the ist from which at test sample was taken or any similar or identical product unless specifically and expressly noted. Our report includes all of the tests requested by you and the results thereof based upon the information that you provided to sure Meximum is only provided upon request for accredited tests. You have 60 days from date of issuance of this report to notify us of any material error or omission caused by our negligence or if you require measurement uncertainty; provided, however, that such notice shall be in writing and shall specifically address the issue you wish to raise. A failure to raise such issue within the prescribed time shall constitute you unqualified acceptance of the completeness of the tests conducted and the correctness of the report cherts.					

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Table of Contents

RF EXPOSURE REPORT	1
Table of Contents	2
RELEASE CONTROL RECORD	
1 GENERAL DESCRIPTION OF EUT	4
2 RF EXPOSURE	5
2.1 EXEMPTION LIMITS FOR ROUTINE EVALU	JATION – RF EXPOSURE
EVALUATION	5
2.2 LIMITS FOR MAXIMUM PERMISSIBLE EXP	OSURE (MPE)6
2.3 MPE CALCULATION FORMULA	6
2.4 CLASSIFICATION	6
2.5 CALCULATION RESULT OF RF EXPOSUR	ER7



RELEASE CONTROL RECORD

ISSUE NO.	REASON FOR CHANGE	DATE ISSUED
SA191017W004	Original release, This test report is for internal customer use only, not as a final certification test report.	Dec. 09, 2019
SAP20120029	Based on the original product add one model name, changed product name. In this report, All test data is copied from the original test report SA191017W004.	Dec. 23, 2020



1 GENERAL DESCRIPTION OF EUT

EUT	Electron			
BRAND NAME	Particle			
MODEL NAME	ELC402, ELC404			
POWER SUPPLY	DC 5V from Host Uint or DC3.7V from Li-ion battery Vnor=3.7V,Vmin=3.145V,Vmax=4.07V			
OPERATING TEMPERATURE RANGE	-20 ~ 60°C			
MODULATION TYPE	LTE	QPSK		
OPERATING FREQUENCY	LTE	1850.7MHz ~ 1909.3MHz (FOR LTE Band2) 1710.7MHz ~ 1754.3MHz (FOR LTE Band4) 824.7MHz ~ 848.3MHz (FOR LTE Band5) 699.7MHz ~ 715.3MHz (FOR LTE Band12) 779.5MHz ~ 784.5MHz (FOR LTE Band13)		
	LTE Band 2	Fixed External Antenna with 3.77dBi gain		
	LTE Band 4	Fixed External Antenna with 3.77dBi gain		
ANTENNA GAIN	LTE Band 5	Fixed External Antenna with 1.42dBi gain		
	LTE Band 12	Fixed External Antenna with 1.4dBi gain		
	LTE Band 13	Fixed External Antenna with 1.4dBi gain		
HW VERSION	V007			
SW VERSION	V1.4.0			
I/O PORTS	Refer to user's manual			
CABLE SUPPLIED	N/A			

NOTE:

1. For a more detailed features description, please refer to the manufacturer's specifications or the user's manual.

 The schematic and PCB of the ELC404 is completely the same with ELC402, and these two models of HW&SW is the same. Because changing the MVNO's E-SIM card (embedded SIM card) provider from Kore to Twilio, so we plan to use different model name to sell it in market. The differences are as follows:ELC402 uses eSIM of Kore.ELC404 uses eSIM of Twilio.

3. For the test results, the EUT had been tested with all conditions. But only the worst case was shown in test report.



Test Report No.: SAP20120029

2 RF EXPOSURE

2.1 EXEMPTION LIMITS FOR ROUTINE EVALUATION - RF EXPOSURE EVALUATION

RF exposure evaluation is required if the separation distance between the user and/or bystander and the device's radiating element is greater than 20 cm, except when the device operates as follows:

- below 20 MHz^{Ecotnote6} and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1 W(adjusted for tune-up tolerance);
- at or above 20 MHz and below 48 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 22.48/f^{0.5} W (adjusted for tune-up tolerance), where f is in MHz;
- at or above 48 MHz and below 300 MHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 0.6 W (adjusted for tune-up tolerance);
- at or above 300 MHz and below 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 1.31 x 10⁻² f^{0.6834} W (adjusted for tune-up tolerance), where f is in MHz;
- at or above 6 GHz and the source-based, time-averaged maximum e.i.r.p. of the device is equal to or less than 5 W (adjusted for tune-up tolerance).

In these cases, the information contained in the RF exposure technical brief may be limited to information that demonstrates how the e.i.r.p. was derived



2.2 LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Table 4: RF Field Strength Limits for Devices Used by the General Public (Uncontrolled Environment)					
Frequency Range (MHz)	Electric Field (V/m rms)	Magnetic Field (A/m rms)	Power Density (W/m ²)	Reference Period (minutes)	
0.003-10 ²¹	83	90	-	Instantaneous*	
0.1-10	-	0.73/ f	-	6**	
1.1-10	87/ f ^{0.5}	-	-	6**	
10-20	27.46	0.0728	-2	6	
20-48	58.07/ f ^{0.25}	0.1540/ f ^{0.25}	8.944/ f ^{0.5}	6	
48-300	22.06	0.05852	1.291	6	
300-6000	3.142 f ^{0.3417}	0.008335 f ^{0.3417}	0.02619 f ^{0.6834}	6	
6000-15000	61.4	0.163	10	6	
15000-150000	61.4	0.163	10	616000/ f ^{1.2}	
150000-300000	0.158 f ^{0.5}	4.21 x 10 ⁻⁴ f ^{0.5}	6.67 x 10 ⁻⁵ f	616000/f ^{1.2}	

Note: f is frequency in MHz.

* Based on nerve stimulation (NS).

** Based on specific absorption rate (SAR).

2.3 MPE CALCULATION FORMULA

 $Pd = (Pout^{*}G) / (4^{*}Pi^{*}R^{2})$

where

 $Pd = power density in W/m^2$

Pout = output power to antenna in W

G = gain of antenna in linear scale

Pi = 3.1416

R = distance between observation point and center of the radiator in m

2.4 CLASSIFICATION

This equipment complies with IC radiation exposure limits set forth for an uncontrolled environment. The antenna of this equipment, under normal use condition, is at least 20cm away from the body of the user. The limit is designed to provide reasonable protection against harmful interference in a residential installation.



Test Report No.: SAP20120029

2.5 CALCULATION RESULT OF RF EXPOSURER

LTE

Band	Frequency (MHz)	Operating Mode	Antenna Gain (dBi)	Tune-up Power (dBm)	Tune-up Power (W)	Exemption Limit (W)	Evaluation Result
Band2	1850-1910	QPSK	3.77	23.00	0.9456	2.24	N/A
Band4	1710-1755	QPSK	3.77	23.00	0.9456	2.12	N/A
Band5	824-849	QPSK	1.42	23.50	0.6179	1.29	N/A
Band12	699-716	QPSK	1.4	24.00	0.6893	1.15	N/A
Band13	780-785	QPSK	1.4	24.00	0.6893	1.24	N/A

Remark: The "N/A" means that, according to the result, LTE Band 2/LTE Band 4/LTE Band 5/LTE Band 12 /LTE Band 13 Max. e.i.r.p. is less than 1.31 x $10^{-2} f^{0.6834}$ W (when *f* is in MHz), so it is exempt from RF Exposure Evaluation.